

Notice of References Cited

Application Control No.

09 628 116

Applicant(s) Patent Under

Reexamination

SOBOLEW, SKI, ET AL

Examiner

Timothy J. Moran

Art Unit

2878

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U.S. PATENT DOCUMENTS

★		Document Number	Date	Name	Classification
		Country Code-Number-Kind Code	MM-YYYY		
	A	US-			
	B	US-			
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

★		Include as applicable: Author Title Date Publisher Edition or Volume Pertinent Pages				
	U	Ghis et al. "Electrical processord measurements of the photoresponse in YBa2Cu3O7-x;" Appl. Phys. Lett. 63: 551 (1993)				
	V					
	W					
	X					

*Active if the reference is being furnished with the application. See MPEP § 1101. A
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